

# Crystal Structure Analysis

## Principles and Practice

Second Edition

**Alexander J. Blake**

*School of Chemistry, University of Nottingham*

**William Clegg**

*Department of Chemistry, University of Newcastle upon Tyne*

**Jacqueline M. Cole**

*Cavendish Laboratory, University of Cambridge*

**John S.O. Evans**

*Department of Chemistry, University of Durham*

**Peter Main**

*Department of Physics, University of York*

**Simon Parsons**

*Department of Chemistry, University of Edinburgh*

**David J. Watkin**

*Chemical Crystallography Laboratory, University of Oxford*

Edited by

**William Clegg**

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